

## Features

- Operating Voltage: 3.3V
- Access Time: 40 ns
- Very Low Power Consumption
  - Active: 180 mW (Max)
  - Standby: 70  $\mu$ W (Typ)
- Wide Temperature Range: -55°C to +125°C
- 400 Mils Width Package
- TTL Compatible Inputs and Outputs
- Asynchronous
- Designed on 0.35 Micron Process
- Latch-up Immune
- 200 Krads capability
- SEU LET Better Than 3 MeV

## Description

The M65609E is a very low power CMOS static RAM organized as 131,072 x 8 bits.

Atmel brings the solution to applications where fast computing is as mandatory as low consumption, such as aerospace electronics, portable instruments, or embarked systems.

Utilizing an array of six transistors (6T) memory cells, the M65609E combines an extremely low standby supply current (Typical value = 20  $\mu$ A) with a fast access time at 40 ns over the full military temperature range. The high stability of the 6T cell provides excellent protection against soft errors due to noise.

The M65609E is processed according to the methods of the latest revision of the MIL STD 883 (class B or S), ESA SCC 9000 or QML.

It is produced on the same process as the MH1RT sea of gates series.



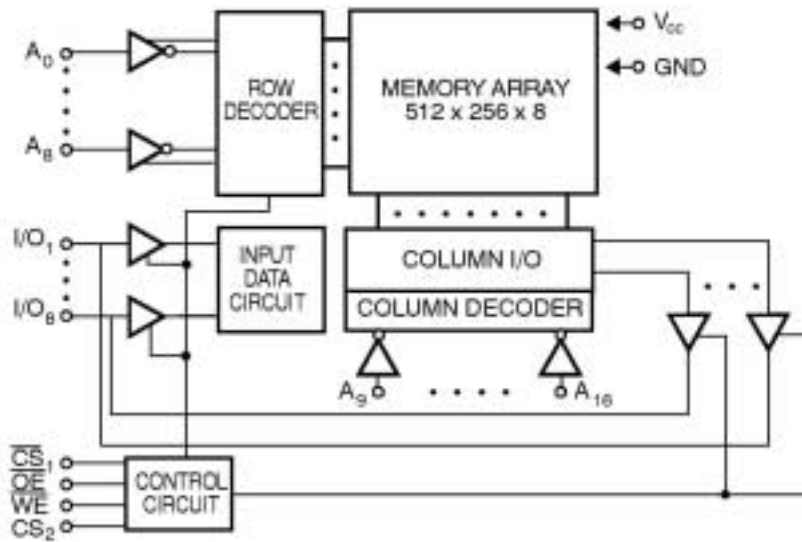
**Rad. Hard**  
**128K x 8**  
**3.3-volt**  
**Very Low Power**  
**CMOS SRAM**

**M65609E**

Rev. 4158D-AERO-06/02



## Block Diagram



## Pin Configuration

32 pins Flatpack 400 MILS



## Pin Description

Table 1. Pin Names

Name	Description
A0 - A16	Address Inputs
I/O1 - I/O8	Data Input/Output
$\overline{CS}_1$	Chip Select 1
$CS_2$	Chip Select 2
$\overline{WE}$	Write Enable
OE	Output Enable
$V_{CC}$	Power
GND	Ground

Table 2. Truth Table

$\overline{CS}_1$	$CS_2$	$\overline{WE}$	$\overline{OE}$	Inputs/ Outputs	Mode
H	X	X	X	Z	Deselect/ Power-down
X	L	X	X	Z	Deselect/ Power-down
L	H	H	L	Data Out	Read
L	H	L	X	Data In	Write
L	H	H	H	Z	Output Disable

Note: L = low, H = high, X = H or L, Z = high impedance.



## Electrical Characteristics

### Absolute Maximum Ratings

Supply Voltage to GND Potential.....	-0.5V + 5V
DC Input Voltage.....	GND - 0.3V to $V_{CC} + 0.3$
DC Output Voltage High Z State .....	GND - 0.3V to $V_{CC} + 0.3$
Storage Temperature .....	-65°C to + 150°C
Output Current Into Outputs (Low) .....	20 mA
Electro Statics Discharge Voltage.....	> 2001V (MIL STD 883D Method 3015.3)

\*NOTE:

Stresses greater than those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

### Military Operating Range

<b>Operating Voltage</b>	<b>Operating Temperature</b>
3.3V ± 0.3V	-55°C to + 125°C

### Recommended DC Operating Conditions

Parameter	Description	Min	Typ	Max	Unit
$V_{CC}$	Supply voltage	3	3.3	3.6	V
Gnd	Ground	0.0	0.0	0.0	V
$V_{IL}$	Input low voltage	GND - 0.3	0.0	0.8	V
$V_{IH}$	Input high voltage	2.2	–	$V_{CC} + 0.3$	V

### Capacitance

Parameter	Description	Min	Typ	Max	Unit
$C_{IN}^{(1)}$	Input low voltage	–	–	8	pF
$C_{OUT}^{(1)}$	Output high voltage	–	–	8	pF

Note: 1. Guaranteed but not tested.

## DC Parameters

### DC Test Conditions

Parameter	Description	Minimum	Typical	Maximum	Unit
IIX <sup>(1)</sup>	Input leakage current	-1	–	1	μA
IOZ <sup>(1)</sup>	Output leakage current	-1	–	1	μA
VOL <sup>(2)</sup>	Output low voltage	-	–	0.4	V
VOH <sup>(3)</sup>	Output high voltage	2.4	–	–	V

1. Gnd < Vin < V<sub>CC</sub>, Gnd < Vout < V<sub>CC</sub> Output Disabled.
2. V<sub>CC</sub> min. IOL = 1 mA.
3. V<sub>CC</sub> min. IOH = -0.5 mA.

### Consumption

Symbol	Description	65609E-40	Unit	Value
ICCSB <sup>(1)</sup>	Standby supply current	2.5	mA	max
ICCSB <sub>1</sub> <sup>(2)</sup>	Standby supply current	1.5	mA	max
ICCOP <sup>(3)</sup>	Dynamic operating current	50	mA	max

1.  $\overline{CS}_1 \geq V_{IH}$  or  $CS_2 \leq V_{IL}$  and  $\overline{CS}_1 \leq V_{IL}$ .
2.  $CS_1 \geq V_{CC} - 0.3V$  or,  $CS_2 < Gnd + 0.3V$  and  $\overline{CS}_1 \leq 0.2V$
3.  $F = 1/T_{AVAV}$ , I<sub>OUT</sub> = 0 mA,  $\overline{W} = \overline{OE} = V_{IH}$ , Vin = Gnd or V<sub>CC</sub>, V<sub>CC</sub> max.

## Write Cycle

Symbol	Parameter	65609E-40	Unit	Value
$t_{AVAW}$	Write cycle time	35	ns	min
$t_{AVWL}$	Address set-up time	0	ns	min
$t_{AVWH}$	Address valid to end of write	28	ns	min
$t_{DVWH}$	Data set-up time	28	ns	min
$t_{E1LWH}$	$\overline{CS}_1$ low to write end	28	ns	min
$t_{E2HWH}$	$CS_2$ high to write end	28	ns	min
$t_{WLQZ}$	Write low to high Z <sup>(1)</sup>	15	ns	max
$t_{WLWH}$	Write pulse width	28	ns	min
$t_{WHAX}$	Address hold from to end of write	+3	ns	min
$t_{WHDX}$	Data hold time	0	ns	min
$t_{WHQX}$	Write high to low Z <sup>(1)</sup>	0	ns	min

Note: 1. Parameters guaranteed, not tested, with 5 pF output loading (see Section “AC Test Conditions” Figure 2).

## Read Cycle

Symbol	Parameter	65609E-40	Unit	Value
$t_{AVAV}$	Read cycle time	40	ns	min
$t_{AVQV}$	Address access time	40	ns	max
$t_{AVQX}$	Address valid to low Z	3	ns	min
$t_{E1LQV}$	Chip-select <sub>1</sub> access time	40	ns	max
$t_{E1LQX}$	$\overline{CS}_1$ low to low Z <sup>(1)</sup>	3	ns	min
$t_{E1HQZ}$	$\overline{CS}_1$ high to high Z <sup>(1)</sup>	15	ns	max
$t_{E2HQV}$	Chip-select <sub>2</sub> access time	40	ns	max
$t_{E2HQX}$	$CS_2$ high to low Z <sup>(1)</sup>	3	ns	min
$t_{E2LQZ}$	$CS_2$ low to high Z <sup>(1)</sup>	15	ns	max
$t_{GLQV}$	Output Enable access time	12	ns	max
$t_{GLQX}$	$\overline{OE}$ low to low Z <sup>(1)</sup>	0	ns	min
$t_{GHQZ}$	$\overline{OE}$ high to high Z <sup>(1)</sup>	10	ns	max

Note: 1. Parameters guaranteed, not tested, with 5 pF output loading (see Section “AC Test Conditions” Figure 2).

**AC Parameters**

**AC Test Conditions**

Input Pulse Levels: ..... GND to 3.0V  
 Input Rise/Fall Times: ..... 5 ns  
 Input Timing Reference Levels: ..... 1.5V  
 Output loading IOL/IOH (see figure 1 and 2)..... +30 pF

**AC Test Loads Waveforms**

Figure 1

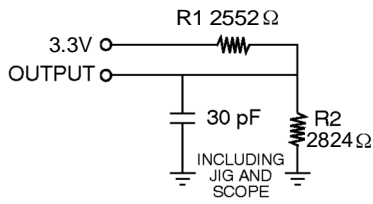


Figure 2

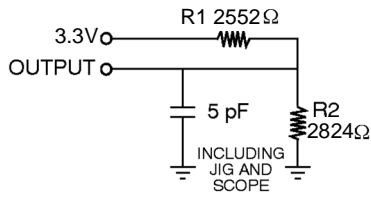
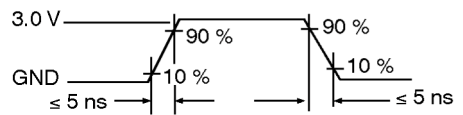
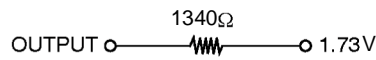


Figure 3



Equivalent to : THEVENIN EQUIVALENT

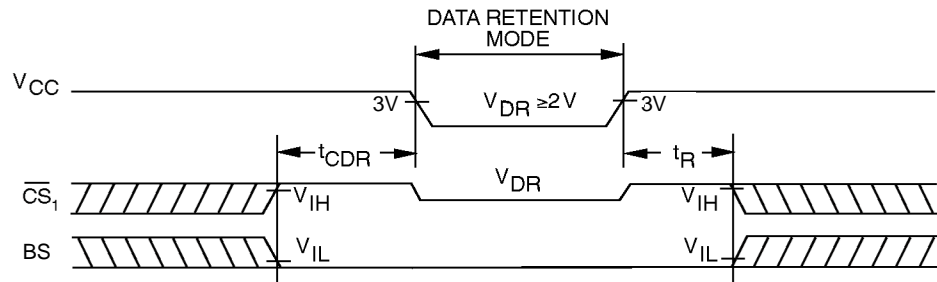


## Data Retention Mode

Atmel CMOS RAM's are designed with battery backup in mind. Data retention voltage and supply current are guaranteed over temperature. The following rules ensure data retention:

1. During data retention  $\overline{CS}$  must be held high within  $V_{CC}$  to  $V_{CC} - 0.2V$  or chip select BS must be held down within GND to GND +0.2V.
2. Output Enable ( $\overline{OE}$ ) should be held high to keep the RAM outputs high impedance, minimizing power dissipation.
3. During power-up and power-down transitions  $\overline{CS}$  and  $\overline{OE}$  must be kept between  $V_{CC} + 0.3V$  and 70% of  $V_{CC}$ , or with BS between GND and GND -0.3V.
4. The RAM can begin operation  $> t_R$  ns after  $V_{CC}$  reaches the minimum operation voltages (3V).

**Figure 1.** Data Retention Timing



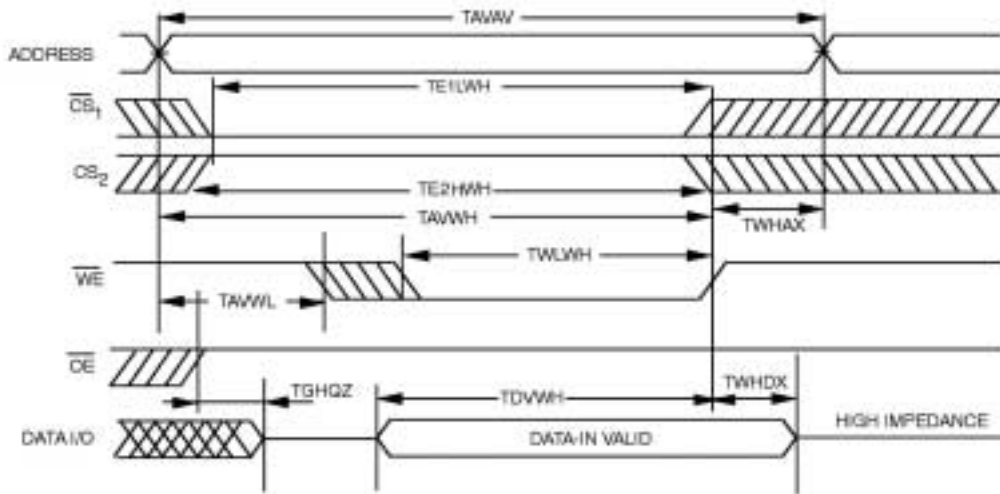
## Data Retention Characteristics

Parameter	Description	Min	Typical $T_A = 25^\circ C$	Max	Unit
$V_{CCDR}$	$V_{CC}$ for data retention	2.0	–	–	V
$T_{CDR}$	Chip deselect to data retention time	0.0	–	–	ns
$t_R$	Operation recovery time	$t_{AVAV}^{(1)}$	–	–	ns
$I_{CCDR1}^{(2)}$	Data retention current at 2.0V	–	0.010	1.0	mA

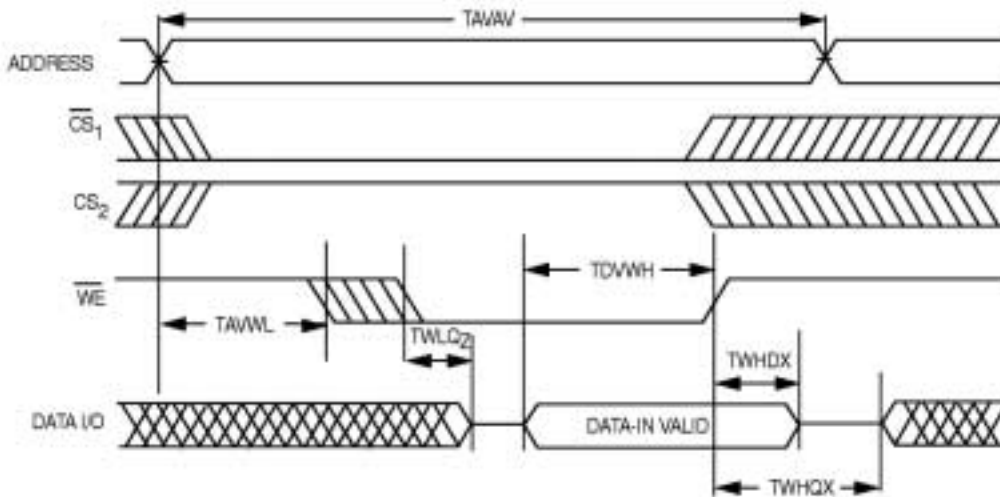
- Notes: 1.  $T_{AVAV}$  = Read Cycle Time  
 2.  $\overline{CS1} = V_{CC}$  or  $\overline{CS2} = \overline{CS1} = GND$ ,  $V_{IN} = GND/V_{CC}$ .



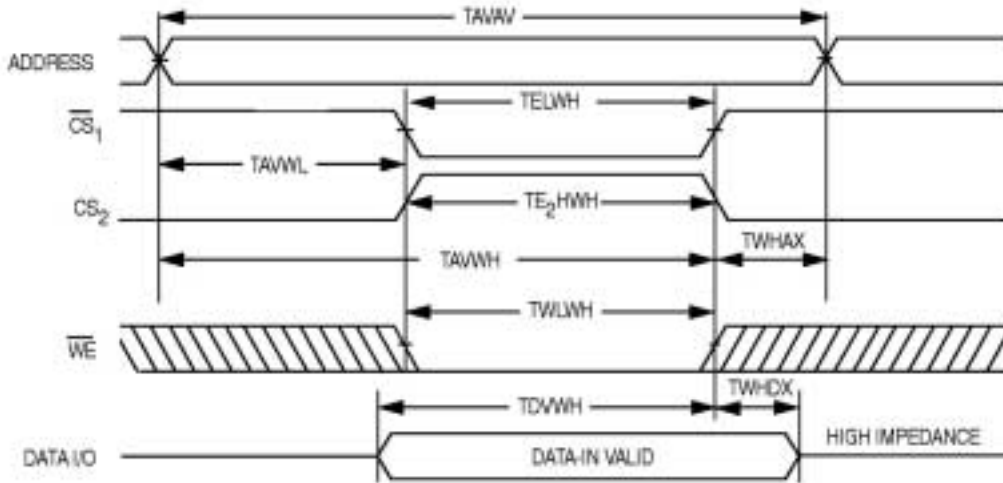
**Write Cycle 1.  $\overline{WE}$  Controlled.  
OE High During Write**



**Write Cycle 2.  $\overline{WE}$  Controlled.  
OE Low**

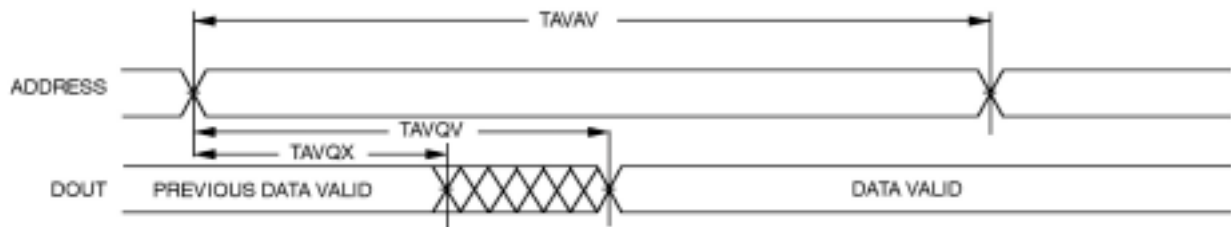


### Write Cycle 3. $\overline{CS1}$ or $CS2$ Controlled<sup>(1)</sup>

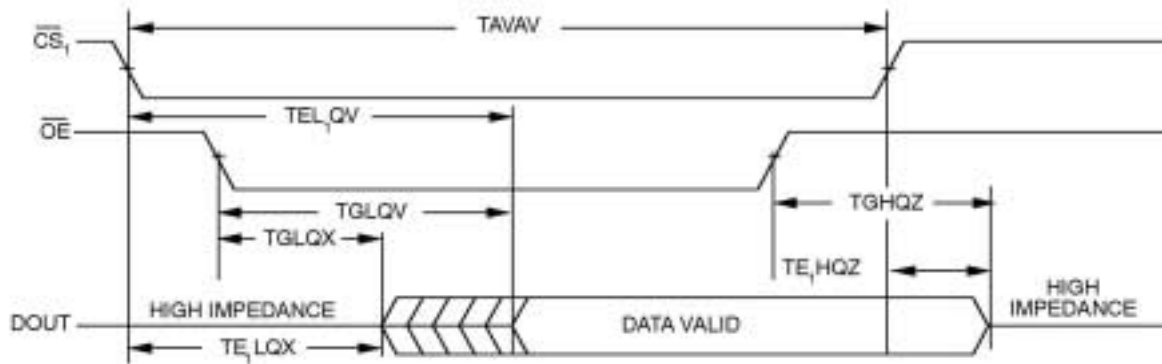


- Note: 1. The internal write time of the memory is defined by the overlap of  $\overline{CS1}$  LOW and  $CS2$  HIGH and  $\overline{WE}$  LOW. Both signals must be activated to initiate a write and either signal can terminate a write by going inactivated. The data input setup and hold timing should be referenced to the activated edge of the signal that terminates the write. Data out is high impedance if  $\overline{OE} = V_{IH}$ .

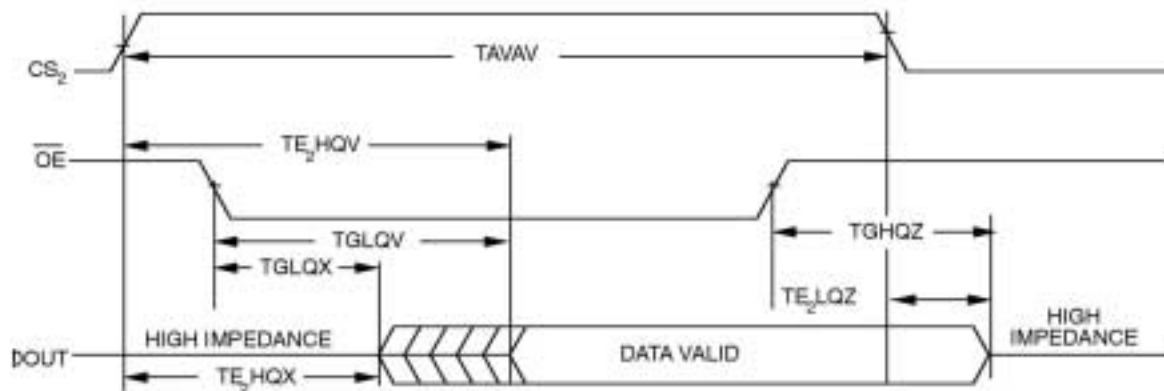
Read Cycle nb 1



Read Cycle nb 2



Read Cycle nb 3



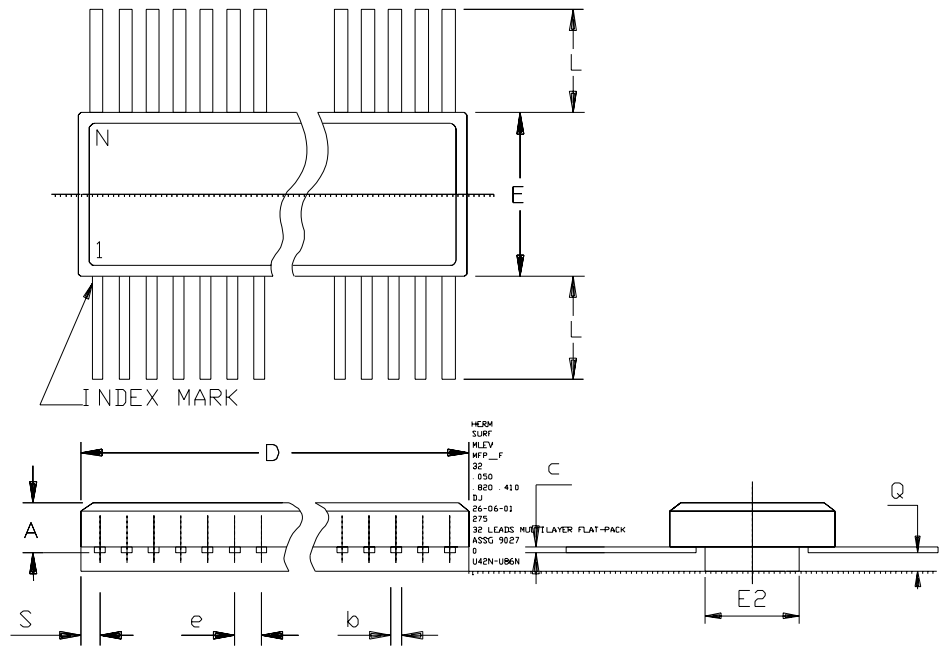
## Ordering Information

Part Number	Temperature Range	Speed	Package	Flow
MMDJ-65609EV-40	-55 to +125°C	40 ns	FP32.4	Standard Mil
MMDJ-65609EV-40MQ	-55 to +125°C	40 ns	FP32.4	QML Q
MMDJ-65609EV-40-E	25°C	40 ns	FP32.4	Engineering Samples
MMDJ-65609EV-40/883 <sup>(1)</sup>	-55 to +125°C	40 ns	FP32.4	MIL 883 B
SMDJ-65609EV-40/883 <sup>(1)</sup>	-55 to +125°C	40 ns	FP32.4	MIL 883 S
MM0-65609EV-40-E	25°C	40 ns	Die	Engineering Samples
MM0-65609EV-40MQ	-55 to +125°C	40 ns	Die	QML Q

Note: 1. Contact Atmel for availability.

Package Drawing

32-pin Flat Pack (400 Mils)



	MM		INCH	
	Min	Max	Min	Max
A	1.78	2.72	.070	.107
b	0.38	0.48	.015	.019
c	0.076	0.15	.003	.007
D	20.62	21.03	.812	.828
E	10.26	10.57	.404	.416
E2	6.96	7.26	.274	.286
e	1.27	BSC	.050	BSC
L	7.37	7.87	.290	.310
Q	0.51	0.76	.020	.030
S	---	1.14	---	.045
N	32		32	



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